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PTO-1449	RMATION DISCLOS	URE CITATION	Attomey Docket No.: 3003-1183	1	NEW NATIONAL PHASE				
INFOR	IN AN APPLICA		Applicant: David EZRA						
	(Use several sheets if n	ecessary)	Filing Date: July 18, 2006		Group Art Unit:				
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^{*} English language abstract provided for the Examiner's convenience

INFORMATION DISCLOSURE CITATION					Attorney Docket No.: 3003-1183		Application No.: 10/586,361			
PER	IN AN APPLICAT	ION			Applicant: David EZRA					
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